

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/535,629	SCOTT, JEFFREY W.	
Examiner		Art Unit		Page 1 of 1
Tuan N Nguyen		2828		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,567,435	05-2003	Scott et al.	372/29.021
	B	US-6,069,905	05-2000	Davis et al.	372/43
	C	US-5,577,064	11-1996	Swirhun et al.	372/96
	D	US-5,953,355	09-1999	Kiely et al.	372/43
	E	US-5,136,152	08-1992	Lee, Wai-Hon	257/699
	F	US-5,812,582	09-1998	Gilliland et al.	372/50
	G	US-5,361,244	11-1994	Nakamura et al.	369/44.23
	H	US-6,670,599	12-2003	Wagner et al.	250/214.1
	I	US-6,160,834	12-2000	Scott, Jeffrey W.	372/96
	J	US-5,115,441	05-1992	Kopf et al.	372/45
	K	US-5,434,939	07-1995	Matsuda, Kenichi	385/88
	L	US-6,246,123	06-2001	Landers et al.	257/787
	M	US-6,417,017	07-2002	Ih, Teng-Yul	438/22

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.